

Title (en)
ELECTROSTATIC FORCE DETECTOR WITH CANTILEVER FOR AN ELECTROSTATIC FORCE MICROSCOPE

Title (de)
ELEKTROSTATISCHER KRAFTMESSFÜHLER MIT FREITRAGENDEN AUSLEGER FÜR EIN ELEKTRO- STATISCHES KRAFTMIKROSKOP

Title (fr)
DETECTEUR DE FORCE ELECTROMAGNETIQUE COMPORTANT UNE PARTIE EN PORTE-A-FAUX, POUR MICROSCOPE A FORCE ELECTROSTATIQUE

Publication
EP 1032828 B1 20141210 (EN)

Application
EP 98955211 A 19981030

Priority
• US 9823059 W 19981030
• US 6393697 P 19971031

Abstract (en)
[origin: WO9923483A1] An atomic force microscope using a cantilevered sensor (12) which is influenced by an electrostatic force given by the charge in the Unit Under Test (40). The cantilever sensor is preferably made of nickel foil. Both charge distribution and thickness of the sample are plotted in a 3D graph.

IPC 8 full level
G01B 7/34 (2006.01); **G01Q 40/00** (2010.01); **B82Y 35/00** (2011.01); **G01N 27/60** (2006.01); **G01Q 60/30** (2010.01); **G01Q 60/40** (2010.01); **G01R 29/12** (2006.01)

CPC (source: EP US)
G01Q 40/00 (2013.01 - EP US); **G01Q 60/30** (2013.01 - EP US); **G01Q 60/40** (2013.01 - EP US); **Y10S 977/852** (2013.01 - EP US); **Y10S 977/864** (2013.01 - EP US)

Citation (examination)
EP 0448985 A1 19911002 - IBM [US]

Designated contracting state (EPC)
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DOCDB simple family (publication)
WO 9923483 A1 19990514; CN 1138980 C 20040218; CN 1285915 A 20010228; EP 1032828 A1 20000906; EP 1032828 A4 20010509; EP 1032828 B1 20141210; JP 2001522045 A 20011113; JP 4584446 B2 20101124; US 6507197 B1 20030114

DOCDB simple family (application)
US 9823059 W 19981030; CN 98812846 A 19981030; EP 98955211 A 19981030; JP 2000519295 A 19981030; US 18308298 A 19981030